



## Advances in Low-Frequency Noise Measurements

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Deadline for manuscript  
submissions:

**closed (31 January 2022)**

### Message from the Guest Editor

This Special Issue focuses on the latest advances in the field of low-frequency noise measurements, with a particular focus on experimental results relating to new and advanced electron devices, applications in the field of quality and reliability, measurement methodologies, and dedicated instrumentation. Topics of interest include, but are not limited to, the following:

- Low-frequency noise in electron devices and circuits;
- Low-frequency noise in advanced materials;
- Low-frequency noise in optical devices;
- Low-frequency noise measurement methodologies and instrumentation;
- Application of low-frequency noise to the evaluation of the quality and reliability of electron devices and systems;
- Low-frequency noise simulation and modeling.

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## Editor-in-Chief

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## Message from the Editor-in-Chief

*Electronics* is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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